Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination MURAKAMI ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0012406	01-2003	Iwamura, Keiichi	382/100
*	В	US-2003/0123698	07-2003	Murakami, Tomochika	382/100
*	С	US-2003/0009674	01-2003	Pelly et al.	713/176
	D	US-			
	E	US-			
	E	US-		·	
	G	US-			>
	Н	US-			
	j	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

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